

L Number	Hits	Search Text	DB	Time stamp
1	2	6490368.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 11:33
6	10	382/147	US-PGPUB	2003/09/05 11:42
-	2	4926452.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 11:33
-	2	5081656.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:20
-	2	5097492.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:20
-	2	5199054.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:21
-	2	5259012.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:22
-	2	5291535.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:22
-	2	5561696.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:23
-	2	5583904.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:24
-	2	5621811.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:41
-	2	5687209.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:25
-	118	378/22.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:30
-	216	382/147.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:30

-	324	378/21.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:31
-	1287	((identify\$3 or inspect\$3 or evaluat\$3) with solder\$3 with (joint\$1 or connection\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:17
-	21	((identify\$3 or inspect\$3 or evaluat\$3) with solder\$3 with (joint\$1 or connection\$1)) and ((distance or space or gap) with (mount\$3 with surface\$1 with board))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 11:42
-	65	((identify\$3 or inspect\$3 or evaluat\$3) with solder\$3 with (joint\$1 or connection\$1)) and ((distance or space or gap) with ( surface\$1 with board))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:07
-	5	((identify\$3 or inspect\$3 or evaluat\$3) with solder\$3 with (joint\$1 or connection\$1)) and (neighbor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:08
-	683	((distance or space or gap) with (mount\$3 with surface\$1 with board) same (printed with circuit))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:17
-	612	((distance or space) with (mount\$3 with surface\$1 with board) same (printed with circuit))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:17
-	10	((distance or space or gap) with (mount\$3 with surface\$1 with board) same (printed with circuit))) and ((defect\$1 or quality) with solder\$3 with (joint\$1 or connection\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:27
-	0	((identify\$3 or inspect\$3 or evaluat\$3) with solder\$3 with (joint\$1 or connection\$1)) and (box adj plot)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:28
-	73	box adj plot	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:28
-	64	(box adj plot) and (analy\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:28
-	1	((box adj plot) and (analy\$4)) and (solder)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:28
-	185363	(chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:18

-	33687	((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria) ) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:25
-	3	((((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria) ) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5)) ) and (((printed adj circuit adj board) with solder with joint\$1) same ((location or position) with solder with (joint\$1 or connection\$1))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:26
-	1	(((((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria) ) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5)) ) and (((printed adj circuit adj board) with solder with joint\$1) same ((location or position) with solder with (joint\$1 or connection\$1)))) ) and ((distance or space) with mount\$3 with surface with board with device)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:56
-	438825	((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:25
-	49	((((printed adj circuit adj board) with solder with joint\$1) same ((location or position) with solder with (joint\$1 or connection\$1))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:53
-	380	((distance or space) with mount\$3 with surface with board with device)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:27
-	1	(((((printed adj circuit adj board) with solder with joint\$1) same ((location or position) with solder with (joint\$1 or connection\$1)))) ) and ((distance or space) with mount\$3 with surface with board with device) )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:27
-	92	((((printed adj circuit adj board) with solder with joint\$1) and ((location or position) with solder with (joint\$1 or connection\$1))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 16:03
-	6	(((((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria) ) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5)) ) and (((printed adj circuit adj board) with solder with joint\$1) and ((location or position) with solder with (joint\$1 or connection\$1)))) )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:56

-	1	(((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria) ) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5)) ) and (((printed adj circuit adj board) with solder with joint\$1) and ((location or position) with solder with (joint\$1 or connection\$1))) ) and ((distance or space) with mount\$3 with surface with board with device)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:56
-	1514	((location or position) with solder with (joint\$1 or connection\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 16:03
-	239	((distance or space) with mount\$3 with surface with (circuit with board) with device\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 16:04
-	1	(((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria) ) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5)) ) and (((location or position) with solder with (joint\$1 or connection\$1)) ) and (((distance or space) with mount\$3 with surface with (circuit with board) with device\$1) )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 16:05
-	5	(((location or position) with solder with (joint\$1 or connection\$1)) ) and (((distance or space) with mount\$3 with surface with (circuit with board) with device\$1) )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 16:06
-	21	(((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria) ) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5)) ) and (((location or position) with solder with (joint\$1 or connection\$1)) )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 11:53
-	1	((distance adj between) with (mounting adj surface) with device with (circuit adj board) with solder with (joint\$1 or connection\$1)) and (location or position)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 15:36
-	1	((distance or space) with (mounting adj surface) with device with (circuit adj board) with solder with (joint\$1 or connection\$1)) and (location or position)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 15:38
-	3	((distance or space) with (moun\$3 with surface) with device with (circuit adj board) with solder with (joint\$1 or connection\$1)) and (location or position)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 15:39
-	8	((distance or space or gap) with surface with device with (circuit adj board)) and (solder with (joint\$1 or connection\$1))and (location or position)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 16:17

-	3	((distance or space or gap) with surface with device with (circuit adj board)) and (solder with (joint\$1 or connection\$1))and (location or position) ) and (threshold or criteria or range or limit)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 15:53
-	1	((distance or space) with (mounting adj surface) with device with (circuit adj board) with solder with (joint\$1 OR connection\$1)) AND (location OR position)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 15:53
-	84	((distance or space or gap) with surface with device with (circuit adj board)) and (solder with (joint\$1 or connection\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 07:30
-	1	RE35,423.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 07:32
-	2	6,580,501.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 07:31
-	2	5,780,866.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 07:31
-	2	4,792,683.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 07:31
-	219	702/35.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 11:26
-	181	702/33.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 11:26